



US005987095A

**United States Patent** [19]  
**Chapman et al.**

[11] **Patent Number:** **5,987,095**  
[45] **Date of Patent:** **Nov. 16, 1999**

[54] **METHOD FOR DETECTING AN IMAGE OF AN OBJECT**

[76] Inventors: **Leroy Dean Chapman**, 4 Vermont Cir., Bolingbrook, Ill. 60440; **William C. Thomlinson**, 32 E. Masem, East Patchogue, N.Y. 11772; **Zhong Zhong**, Apt. I 1131 Chaping 700 E. Loop Rd., Stonybrook, N.Y. 11790

[21] Appl. No.: **08/936,250**  
[22] Filed: **Sep. 24, 1997**

**Related U.S. Application Data**

[63] Continuation of application No. 08/732,613, Oct. 16, 1996.

[51] **Int. Cl.<sup>6</sup>** ..... **G01N 23/04**  
[52] **U.S. Cl.** ..... **378/70; 378/84; 378/98.12**  
[58] **Field of Search** ..... **378/62, 70, 71, 378/84, 87, 37, 36, 98.12**

[56] **References Cited**

**U.S. PATENT DOCUMENTS**

4,599,741	7/1986	Wittry	378/85
5,245,648	9/1993	Kinney et al.	378/43
5,259,013	11/1993	Kuriyama et al.	378/43
5,319,694	6/1994	Ingal et al.	378/84
5,579,363	11/1996	Ingal et al.	378/84

**FOREIGN PATENT DOCUMENTS**

95 05725 2/1995 WIPO .

**OTHER PUBLICATIONS**

Tetsuya Ishikawa, Seishi Kikuta and Kazutaka Kohra, Angle-Resolved Plane Wave X-Ray Topography, *Japanese Journal of Applied Physics*, vol. 24, No. 7, Jul., 1985, pp. L559-L562.

R.C. Blasdel and A.T. Macrander, Prototype grooved and spherically bent Si backscattering crystal analyzer for meV resolution inelastic x-ray scattering, *Review of Scientific Instruments*, vol. 66, No. 2, Feb. 1995, pp. 2075-2077, New York.

D. Chapman, W. Thomlinson, R.E. Johnson, D. Washburn, E. Pisano, N. Gmür, Z. Zhong, R. Menk, F. Arfelli and D.

Sayers, *X-Ray Refraction Imaging (XRI) Applied to Mammography*, published Oct. 31, 1997.

V.N. Ingal and E.A. Beliaevskaya, *Phase Dispersion Introscopy*, (published prior to Oct. 16, 1996).

V.N. Ingal and E.A. Beliaevskaya, *Phase Dispersion Introscopy, Surface Investigation*, vol. 12, pp. 441-450, 1997.

V.A. Bushuev, V.N. Ingal and E.A. Belyaevskaya, Dynamical Theory of Images Generated by Noncrystalline Objects for the Method of Phase-Dispersive Introscopy, *Crystallography Reports*, vol. 41, No. 5, 1996, pp. 766-774.

V.A. Bushuev, E.A. Beliaevskaya and V.N. Ingal, Wave-optical description of X-ray phase contrast images of weakly absorbing non-crystalline objects, *Il Nuovo Cimento*, vol. 19D, No. 2-4, Feb.-Apr. 1997.

V.N. Ingal and E.A. Beliaevskaya, Imaging of biological objects in the plane-wave diffraction scheme, *Il Nuovo Cimento*, vol. 19D, No. 2-4, Feb.-Apr. 1997.

V.N. Ingal and E.A. Beliaevskaya, X-ray plane-wave topography observation of the phase contrast from a non-crystalline object, *J. Phys. D: Appl. Phys.* 28 (1995) 2314-2317.

V.N. Ingal and E.A. Belyaevskaya, Method of phase-dispersion introscopy, *Tech. Phys.* 42 (1), Jan. 1997.

V.N. Ingal and E.A. Beliaevskaya, Phase dispersion radiography of biological objects, *Physica Medica*, vol. X11, No. 2, Apr.-Jun. 1996.

*Primary Examiner*—David P. Porta

*Attorney, Agent, or Firm*—Pauley Petersen Kinne & Fejer

[57] **ABSTRACT**

A method for detecting an absorption, refraction and scatter image of an object by independently analyzing, detecting, digitizing, and combining images acquired on a high and a low angle side of a rocking curve of a crystal analyzer. An x-ray beam which is generated by any suitable conventional apparatus can be irradiated upon either a Bragg type crystal analyzer or a Laue type crystal analyzer. Images of the absorption, refraction and scattering effects are detected, such as on an image plate, and then digitized. The digitized images are simultaneously solved, preferably on a pixel-by-pixel basis, to derive a combined visual image which has dramatically improved contrast and spatial resolution over an image acquired through conventional radiology methods.

**19 Claims, 6 Drawing Sheets**

